PATENT ASSIGNMENT COVER SHEET

Electronic Version v1.1
Stylesheet Version v1.2

EPAS ID: PAT4470256

SUBMISSION TYPE:	CORRECTIVE ASSIGNMENT
NATURE OF CONVEYANCE:	Corrective Assignment to correct the ASSIGNEE'S COUNTRY previously recorded on Reel 042414 Frame 0385. Assignor(s) hereby confirms the THE CORRECTION OF COUNTRY FROM UNITED KINGDOM TO FINLAND.

CONVEYING PARTY DATA

Name	Execution Date
OXFORD INSTRUMENTS ANALYTICAL OY	03/29/2017

RECEIVING PARTY DATA

Name:	OXFORD INSTRUMENTS INDUSTRIAL
Street Address:	C/O DERBY BUSINESS PARK TARVONSALMENKATU 17
Internal Address:	PL 85 02631
City:	ESPOO
State/Country:	FINLAND
Postal Code:	02600

PROPERTY NUMBERS Total: 12

Property Type	Number
Patent Number:	6049589
Patent Number:	6934021
Patent Number:	7065174
Patent Number:	7020238
Patent Number:	7233643
Patent Number:	7203283
Patent Number:	7426019
Patent Number:	7409037
Patent Number:	7443959
Patent Number:	7474730
Patent Number:	7394537
Patent Number:	7508906

CORRESPONDENCE DATA

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ATTORNEY DOCKET NUMBER:	10197Z99995
NAME OF SUBMITTER:	F. WILLIAM MCLAUGHLIN
SIGNATURE:	/F. William McLaughlin/
DATE SIGNED:	06/21/2017

Total Attachments: 6
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PATENT ASSIGNMENT COVER SHEET

Electronic Version v1.1
Stylesheet Version v1.2

EPAS ID: PAT4418888

SUBMISSION TYPE:	NEW ASSIGNMENT
NATURE OF CONVEYANCE:	ASSIGNMENT

CONVEYING PARTY DATA

Name	Execution Date
OXFORD INSTRUMENTS ANALYTICAL OY	03/29/2017

RECEIVING PARTY DATA

Name:	OXFORD INSTRUMENTS INDUSTRIAL ANALYSIS OY
Street Address:	C/O DERBY BUSINESS PARK TARVONSALMENKATU 17
Internal Address:	PL 85 02631
City:	ESPOO
State/Country:	UNITED KINGDOM
Postal Code:	02600

PROPERTY NUMBERS Total: 12

Property Type	Number
Patent Number:	6049589
Patent Number:	7065174
Patent Number:	7020238
Patent Number:	6934021
Patent Number:	7409037
Patent Number:	7474730
Patent Number:	7443959
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Patent Number:	7233643
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Patent Number:	7394537

CORRESPONDENCE DATA

Fax Number: (312)876-2020

Correspondence will be sent to the e-mail address first; if that is unsuccessful, it will be sent using a fax number, if provided; if that is unsuccessful, it will be sent via US Mail.

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VAHVISTUS /
CONFIRMATION

Oxford Instruments Analytical Oy (Y-tunnus: 1837215-2, myöhemmin myös "**Jakaantuva Yhtiö**") jakautuu selvitysmenettelyttä osakeyhtiölain (624/2006 muutoksineen) 17 luvun ja elinkeinotulon verottamisesta annetun lain (360/1968 muutoksineen) 52 c §:n tarkoittamalla kokonaisjakautumisella siten, että kaikki Jakautuvan Yhtiön varat ja velat siirtyvät kahdelle jakautumisella perustettavalle yhtiölle, Oxford Instruments Industrial Analysis Oy:lle (Y-tunnus 2790541-6) ja Oxford Instruments Technologies Oy:lle (Y-tunnus 2790542-4) (yhdessä "**Vastaanottavat Yhtiöt**") 21. lokakuuta 2016 allekirjoitetun ja 2. marraskuuta 2016 rekisteröidyn jakautumissuunnitelman ("**Jakautumissuunnitelma**") mukaisesti ja Jakautuva Yhtiö purkautuu ("**Jakautuminen**"). Jakautumisen arvioitu täytäntöönpanopäivämäärä on 31. maaliskuuta 2017.

*Oxford Instruments Analytical Oy (Business ID: 1837215-2, later also the "**Demerging Company**") will demerge without a liquidation procedure in accordance with Chapter 17 of the Finnish Companies Act (624/2006 as amended) and Section 52 c of the Finnish Business Income Tax Act (360/1968 as amended) by way of a whole demerger so that all of the assets and liabilities of the Demerging Company are transferred to two acquiring companies incorporated in connection with the demerger, namely Oxford Instruments Industrial Analysis Oy (Business ID 2790541-6; unregistered) and Oxford Instruments Technologies Oy (Business ID 2790542-4; unregistered) (jointly the "**Receiving Companies**") in accordance with the demerger plan dated 21 October 2016 and registered 2 November 2016 (the "**Demerger Plan**") and the Demerging Company will dissolve (the "**Demerger**"). The estimated implementation date of the Demerger is 31 March 2017.*

Jakautuva Yhtiö vahvistaa täten, että Jakautumisen täytäntöönpanon myötä Jakautuvan Yhtiön nimissä olevat patentit ja patenttihakemukset siirtyvät jakautumisen täytäntöönpanopäivänä yleisseuraantona Jakaantumissuunnitelman mukaisesti Vastaanottaville Yhtiöille seuraavasti:

(i) **Liitteessä 1** identifioidut patentit ja patenttihakemukset siirtyvät Oxford Instruments Industrial Analysis Oy:lle (Y-tunnus 2790541-6); ja

(ii) **Liitteessä 2** identifioidut patentit ja patenttihakemukset siirtyvät Oxford Instruments Technologies Oy:lle (Y-tunnus 2790542-4).

The Demerging Company hereby confirms that upon the implementation of the Demerger the patents and patent applications registered to the Demerging Company transfer as of the implementation date of the Demerger in accordance with the Demerger Plan by way of universal succession to the Receiving Companies as set out below:

*(i) Patents and patent applications identified in **Appendix 1** transfer to Oxford Instruments Industrial Analysis Oy (Business ID 2790541-6); and*

*(ii) Patents and patent applications identified in **Appendix 2**l transfer to Oxford Instruments Technologies Oy (Business ID 2790542-4).*

Tämä dokumentti toimii todisteena Jakautuvan Yhtiön yllä todetusta patenttien ja patenttihakemusten siirtymisestä Vastaanottaville Yhtiöille Vastaanottavien Yhtiöiden sanottujen patenttien omistusoikeuden rekisteröimistä varten asianomaisissa patenttirekistereissä.

This document shall serve as a proof of transfer of the patents and patent applications of the Demerging Company to the Receiving Companies in accordance with the above for the purpose of recording the Receiving Companies' ownership in the subject patents in each relevant patent register.

[allekirjoitukset seuraavalla sivulla / *signatures on the following page*]

Päiväys / *Date*: 29/03/2017
Paikka / *Location*: Oxford, UK

OXFORD INSTRUMENTS ANALYTICAL OY

Dawn Brooks
Hallituksen puheenjohtaja /
Chairman of the Board of Directors

Ian Barkshire
Hallituksen jäsen /
Member of the Board of Directors

James Jefferson
Hallituksen jäsen /
Member of the Board of Directors

LIITTEET
APPENDICES

Liite 1 / ***Appendix 1*** Oxford Instruments Industrial Analysis Oy:lle siirtyvät patentit ja patenttihakemukset / *Patents and patent applications transferred to Oxford Instruments Industrial Analysis Oy*

Liite 2 / ***Appendix 2*** Oxford Instruments Technologies Oy:lle siirtyvät patentit ja patenttihakemukset / *Patents and patent applications transferred to Oxford Instruments Technologies Oy*

Patents - Oxford Instruments Industrial Analysis OY

Client's Reference / Title	Country	Applicant Name	Application No.	Appln Date	Pub or Grant No.	If granted: Grant Date
X-ray tube whose end window carries two anode layers, and an X-ray fluorescence analyzer	FR	OXFORD INSTRUMENTS ANALYTICAL OY	7102233.9	13/02/2007	1821583	26/11/2008
X-ray tube whose end window carries two anode layers, and an X-ray fluorescence analyzer	DE	OXFORD INSTRUMENTS ANALYTICAL OY	07102233.9	13/02/2007	602007000264.8-08	26/11/2008
X-ray tube whose end window carries two anode layers, and an X-ray fluorescence analyzer	IT	OXFORD INSTRUMENTS ANALYTICAL OY	07102233.9	13/02/2007	1821583	26/11/2008
X-ray tube whose end window carries two anode layers, and an X-ray fluorescence analyzer	NL	OXFORD INSTRUMENTS ANALYTICAL OY	07102233.9	13/02/2007	1821583	26/11/2008
X-ray tube whose end window carries two anode layers, and an X-ray fluorescence analyzer	UK	OXFORD INSTRUMENTS ANALYTICAL OY	07102233.9	13/02/2007	1821583	26/11/2008
X-ray tube whose end window carries two anode layers, and an X-ray fluorescence analyzer	Switzerland + Liechtenstein	OXFORD INSTRUMENTS ANALYTICAL OY	07102233.9	13/02/2007	1821583	26/11/2008
X-ray fluorescence measuring system making use of polarized excitation radiation, and X-ray tube	US	OXFORD INSTRUMENTS ANALYTICAL OY	09/103389	24/06/1998	6049589	11/04/2000
Method and arrangements for detecting the 193 nm spectral line of carbon by emission spectroscopy	Finland	OXFORD INSTRUMENTS ANALYTICAL OY	20021666	18/09/2002	115999	31/08/2005
Method and arrangements for detecting the 193 nm spectral line of carbon by emission spectroscopy	EP	OXFORD INSTRUMENTS ANALYTICAL OY	03396085.7	15/09/2003	1400793	09/08/2006
Method and arrangements for detecting the 193 nm spectral line of carbon by emission spectroscopy	Russia	OXFORD INSTRUMENTS ANALYTICAL OY	2003128927	17/09/2003	2319937	20/03/2008
Improved measurement arrangement for x-ray fluorescence analysis	US	OXFORD INSTRUMENTS ANALYTICAL OY	10/987145	12/11/2004	7065174	20/06/2006
Adapter and Analyzer Device for Performing X-Ray Fluorescence Analysis on Hot Surfaces	US	OXFORD INSTRUMENTS ANALYTICAL OY	11/047247	31/01/2005	7020238	28/03/2006
Method and arrangements for detecting the 193 nm spectral line of carbon by emission spectroscopy	US	OXFORD INSTRUMENTS ANALYTICAL OY	10/650014	27/08/2003	6934021	23/08/2005
X-ray fluorescence analyzer having means for producing lowered pressure, and an X-ray fluorescence measurement method using lowered pressure	US	OXFORD INSTRUMENTS ANALYTICAL OY	11/429172	05/05/2006	7409037	05/08/2008
Method and arrangements for detecting the 193 nm spectral line of carbon by emission spectroscopy	FR	OXFORD INSTRUMENTS ANALYTICAL OY	03396085.7	15/09/2003	1400793	09/08/2006
Method and arrangements for detecting the 193 nm spectral line of carbon by emission spectroscopy	DE	OXFORD INSTRUMENTS ANALYTICAL OY	03396085.7	15/09/2003	60307390.5-08	09/08/2006
Method and arrangements for detecting the 193 nm spectral line of carbon by emission spectroscopy	IT	OXFORD INSTRUMENTS ANALYTICAL OY	03396085.7	15/09/2003	1400793	09/08/2006
Method and arrangements for detecting the 193 nm spectral line of carbon by emission spectroscopy	UK	OXFORD INSTRUMENTS ANALYTICAL OY	03396085.7	15/09/2003	1400793	09/08/2006
Compensation of fluctuations over time in the radiation characteristics of the X-ray source in an XRF analyser	US	OXFORD INSTRUMENTS ANALYTICAL OY	11/581929	17/10/2006	7474730	06/01/2009
Selective Irradiation of Small Target Area in X-ray Fluorescent Spectroscopy	US	OXFORD INSTRUMENTS ANALYTICAL OY	11/545300	10/10/2006	7443959	28/10/2008
A filter for X-ray radiation, and an arrangement for using filtered X-ray radiation for excitation	US	OXFORD INSTRUMENTS ANALYTICAL OY	11/789854	26/04/2007	7508906	24/03/2009
X-Ray Tube of the End Window Type, and an X-Ray Fluorescence Analyzer	US	OXFORD INSTRUMENTS ANALYTICAL OY	11/358835	21/02/2006	7203283	10/04/2007
X-ray tube whose end window carries two anode layers, and an X-ray fluorescence analyzer	EP	OXFORD INSTRUMENTS ANALYTICAL OY	07102233.9	13/02/2007	1821583	26/11/2008
An X-ray fluorescence analyzer with gas-filled chamber	EP	OXFORD INSTRUMENTS ANALYTICAL OY	08155628.4	05/05/2008	2116842	19/10/2016
An X-ray fluorescence analyzer with gas-filled chamber	DE	OXFORD INSTRUMENTS ANALYTICAL OY	8155628.4	15/01/2010	602008046872.0	19/10/2016
An X-ray fluorescence analyzer with gas-filled chamber	NL	OXFORD INSTRUMENTS ANALYTICAL OY	8155628.4	05/05/2008	2116842	19/10/2016
An X-ray fluorescence analyzer with gas-filled chamber	CH	OXFORD INSTRUMENTS ANALYTICAL OY	8155628.4	05/05/2008	2116842	19/10/2016
X-ray fluorescence analyzer having means for producing lowered pressure, and an X-ray fluorescence measurement method using lowered pressure	EP	OXFORD INSTRUMENTS ANALYTICAL OY	07107430.6	03/05/2007	1852696	16/01/2012
X-ray fluorescence analyzer having means for producing lowered pressure, and an X-ray fluorescence measurement method using lowered pressure	DE	OXFORD INSTRUMENTS ANALYTICAL OY	07107430.6	03/05/2007	602007028045.1	16/01/2013
X-ray fluorescence analyzer having means for producing lowered pressure, and an X-ray fluorescence measurement method using lowered pressure	UK	OXFORD INSTRUMENTS ANALYTICAL OY	07107430.6	03/05/2007	1852696	16/01/2013
Adapter and Analyzer Device for Performing X-Ray Fluorescence Analysis on Hot Surfaces	EP	OXFORD INSTRUMENTS ANALYTICAL OY	06100925.4	27/01/2006	1686369	29/12/2010
Adapter and Analyzer Device for Performing X-Ray Fluorescence Analysis on Hot Surfaces	DE	OXFORD INSTRUMENTS ANALYTICAL OY	06100925.4	27/01/2006	602006019162.6-08	29/12/2010
Adapter and Analyzer Device for Performing X-Ray Fluorescence Analysis on Hot Surfaces	FR	OXFORD INSTRUMENTS ANALYTICAL OY	06100925.4	27/01/2006	1686369	29/12/2010
Adapter and Analyzer Device for Performing X-Ray Fluorescence Analysis on Hot Surfaces	UK	OXFORD INSTRUMENTS ANALYTICAL OY	06100925.4	27/01/2006	1686369	29/12/2010
Spectrometer with multiple gratings	DE	OXFORD INSTRUMENTS ANALYTICAL OY	102008054733.6	16/12/2008	DE102008054733 A1	appln

Appendix 1

PATENT
REEL: 042931 FRAME: 0293

RECORDED: 06/21/2017

PATENT
REEL: 042931 FRAME: 0294

X-ray fluorescence analyzer with safety features	US	OXFORD INSTRUMENTS ANALYTICAL OY	14/034607	24/09/2013	9310324	12/04/2016
Portable analyzer with radiation safety features	US	OXFORD INSTRUMENTS ANALYTICAL OY	14/308995	19/06/2014	2015/0085977 A1	appln
Portable analyzer with radiation safety features	EP	OXFORD INSTRUMENTS ANALYTICAL OY	14184342.5	11/09/2014	2851678 A1	appln
Measurement apparatus and method for determining the material composition of a sample by combined X-ray fluorescence analysis and laser-induced breakdown spectroscopy	US	OXFORD INSTRUMENTS ANALYTICAL OY	11/134740	20/05/2005	7233643	19/06/2007
Method and arrangements for non-destructive composition analysis of delicate samples	US	OXFORD INSTRUMENTS ANALYTICAL OY	11/417689	04/05/2005	7426019	16/09/2008
Practical laser induced breakdown spectroscopy unit	US	OXFORD INSTRUMENTS ANALYTICAL OY	11/644187	22/12/2006	7394537	01/07/2008
Practical laser induced breakdown spectroscopy unit	EP	OXFORD INSTRUMENTS ANALYTICAL OY	07150283.5	21/12/2007	1936361	15/03/2017
Practical laser induced breakdown spectroscopy unit	CH	OXFORD INSTRUMENTS ANALYTICAL OY	07150283.5	21/12/2007	1936361	15/03/2017
Practical laser induced breakdown spectroscopy unit	DE	OXFORD INSTRUMENTS ANALYTICAL OY	07150283.5	21/12/2007	602007050164.4	15/03/2017
Practical laser induced breakdown spectroscopy unit	FI	OXFORD INSTRUMENTS ANALYTICAL OY	07150283.5	21/12/2007	1936361	15/03/2017
Practical laser induced breakdown spectroscopy unit	GB	OXFORD INSTRUMENTS ANALYTICAL OY	07150283.5	21/12/2007	1936361	15/03/2017
Method and arrangements for non-destructive composition analysis of delicate samples	EP	OXFORD INSTRUMENTS ANALYTICAL OY	05103746.3	04/05/2005	1720002	appln
A portable analyzer using optical emission spectroscopy	EP	OXFORD INSTRUMENTS ANALYTICAL OY	17160322.8	10.3.2017		appln